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 U.S. DEPARTMENT OF COMMERCE
 PATENT AND TRADEMARK OFFICE

#7

Sheet 1 of 1

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))	Attorney Docket No.: J&R-0694 Applicant Thomas Zettler Filing Date August 3, 2001 Group Art Unit 2133
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U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
<i>que</i>	A	4,961,053	10/02/90	Krug			
<i>que</i>	B	5,355,081	10/11/94	Nakata et al.			
<i>que</i>	C	6,557,130 B1	04/29/03	Krasser et al.			
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FOREIGN PATENT DOCUMENT

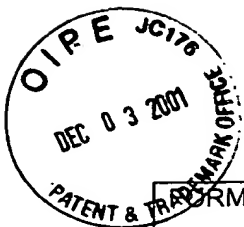
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
<i>que</i>	J	0 974 847 A2	01/26/00	Europe			X
<i>que</i>	K	2000 137 059	05/16/00	Japan			X
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER <i>[Signature]</i>	DATE CONSIDERED <i>6/26/04</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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Sheet 1 of 1

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))	Attorney Docket No.: J&R-0694	Applic. No. 09/922,479
	Applicant Thomas Zettler	
	Filing Date August 3, 2001	Group Art Unit 2133

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
pue	A	5,241,266	08/31/93	Ahmad et al.			
pue	B	5,388,104	02/07/95	Shirotori et al.			
pue	C	5,570,374	10/29/96	Yau et al.			
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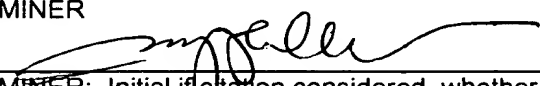
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	NO
pue	J	0 492 624 A1	07/01/92	Europe			X	
pue	K	0 568 239 A2	11/03/93	Europe			X	
pue	L	00 124 279 A	04/28/00	Japan			X	
	M							
	N							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

pue	O	Rangarajan, Sampath et al.: "Built-In Testing of Integrated Circuit Wafers", IEEE Transactions on Computers, Vol. 39, No. 2, February 1990, pp. 195-205
	P	

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